

# **N-Channel Enhancement Mode Power MOSFET**

#### **General Description**

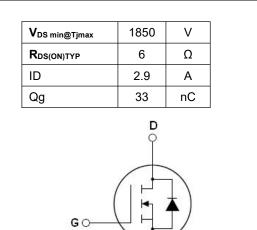
The series of Power MOSFETs use advanced technology and design. This high voltage MOSFET fits Switched applications.

#### Features

- High speed switching
- ●Intrinsic capacitances and Qg minimized
- ●100% Avalanche Tested

## Application

• Switched applications



### Schematic diagram

#### Package Marking And Ordering Information

Device	vice Device Package Marking	
NCE3N170	TO-220	NCE3N170



TO-220

#### Table 1. Absolute Maximum Ratings (Tc=25°C)

Parameter	Symbol	NCE3N170	Unit
Drain-Source Voltage (VGS=0V)	Vds	1700	V
Gate-Source Voltage (VDS=0V) DC	Vgs	±30	V
Continuous Drain Current at Tc=25°C	I <sub>D (DC)</sub>	2.9	A
Continuous Drain Current at Tc=100°C	I <sub>D (DC)</sub>	2.03	A
Pulsed drain current (Note 1)	I <sub>DM (pluse)</sub>	8.7	A
Maximum Power Dissipation(Tc=25°C)	PD	187	W
Derate above 25°C		1.24	W/°C
Single pulse avalanche energy (Note 2)	Eas	210	mJ
Single pulse avalanche current (Note 2)	I <sub>AS</sub>	2.9	A
Operating Junction and Storage Temperature Range	TJ,TSTG	-55+175	°C

\* limited by maximum junction temperature



#### Table 2. Thermal Characteristic

Parameter	Symbol	NCE3N170	Unit
Thermal Resistance, Junction-to-Case (Maximum)	R <sub>thJC</sub>	0.8	°C /W
Thermal Resistance, Junction-to-Ambient (Maximum)	R <sub>thJA</sub>	50	°C /W

## Table 3. Electrical Characteristics (TA=25°C unless otherwise noted)

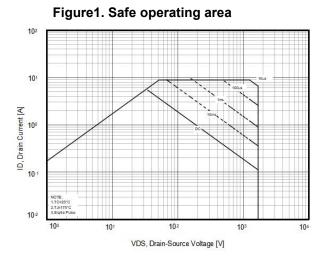
Parameter	Parameter Symbol Condition		Min	Тур	Max	Unit
On/off states						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =1mA 1700				V
Zero Gate Voltage Drain Current(Tc=25°C)	I <sub>DSS</sub>	V <sub>DS</sub> =1700V,V <sub>GS</sub> =0V			1	μA
Zero Gate Voltage Drain Current(Tc=125°C)	IDSS	V <sub>DS</sub> =1700V,V <sub>GS</sub> =0V			100	μA
Gate-Body Leakage Current	Igss	V <sub>GS</sub> =±30V,V <sub>DS</sub> =0V			±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =250µA	3	4	5	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =1.45A		6	8	Ω
Dynamic Characteristics				·		
Input Capacitance	Clss			1700		pF
Output Capacitance	Coss	V <sub>DS</sub> =40V,V <sub>GS</sub> =0V, F=1.0MHz		60		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			3.3		pF
Total Gate Charge	Qg			33		nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> =1350V,I <sub>D</sub> =1.45A, V <sub>GS</sub> =10V		7.7		nC
Gate-Drain Charge	Q <sub>gd</sub>	VGS-10V		14		nC
Intrinsic gate resistance	R <sub>G</sub>	f = 1 MHz open drain		2		Ω
Switching times					•	
Turn-on Delay Time	t <sub>d(on)</sub>			22		nS
Turn-on Rise Time	tr	V <sub>DD</sub> =850V,I <sub>D</sub> =1.45A,		8		nS
Turn-Off Delay Time	t <sub>d(off)</sub>	$R_G=3\Omega, V_{GS}=10V$		48		nS
Turn-Off Fall Time	t <sub>f</sub>			49		nS
Source- Drain Diode Characteristics						
Source-drain current(Body Diode)	Isd	T <sub>c</sub> =25°C			2.9	А
Pulsed Source-drain current(Body Diode)	Isdm	1 <sub>C</sub> -25 C			8.7	А
Forward On Voltage	Vsd	Tj=25°C,I <sub>SD</sub> =2.9A,V <sub>GS</sub> =0V		0.8	1.1	V
Reverse Recovery Time	t <sub>rr</sub>			1500		nS
Reverse Recovery Charge	Qrr	— Tj=25°C,I⊧=2.9A, — — di/dt=100A/μs —		5.6		uC
Peak Reverse Recovery Current	Irrm			7.5		А

Notes 1.Repetitive Rating: Pulse width limited by maximum junction temperature

2. Tj=25°C,VDD=50V,VG=10V, R\_G=25 $\Omega$ 



## **TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (curves)**





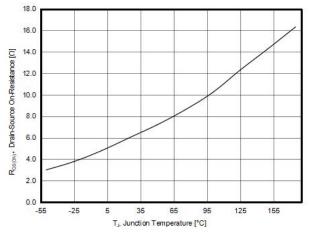
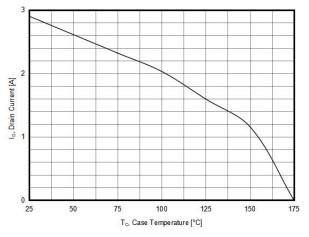
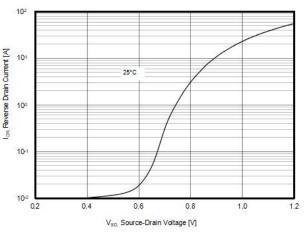


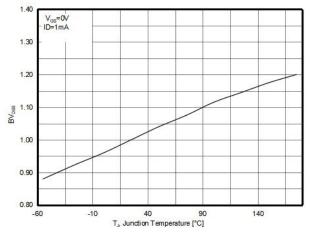
Figure 5. Maximum I<sub>D</sub> vs Junction Temperature



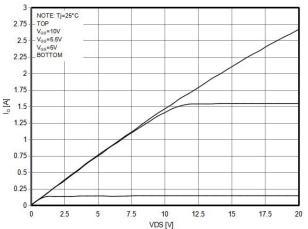
#### Figure2. Source-Drain Diode Forward Voltage





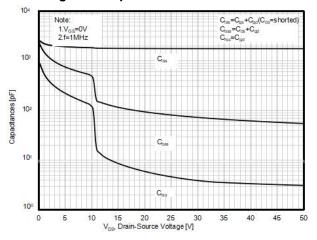


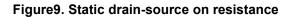
#### Figure6. Output characteristics

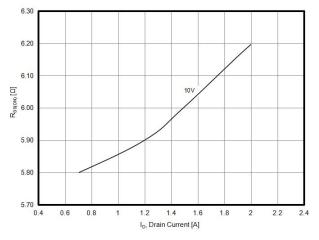


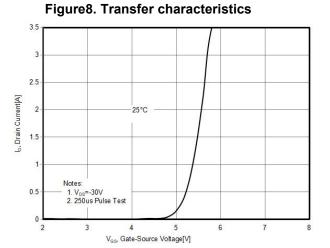


#### Figure7. Capacitance

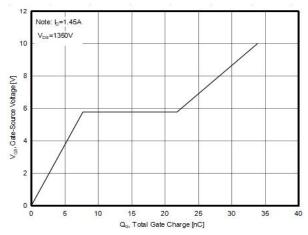








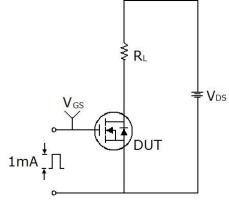


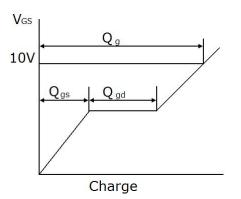




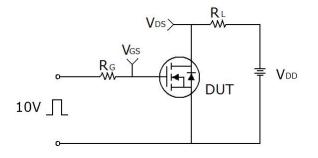
## **Test circuit**

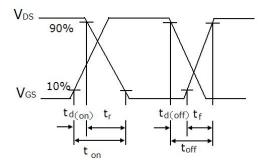
1) Gate charge test circuit & Waveform



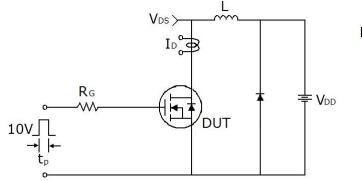


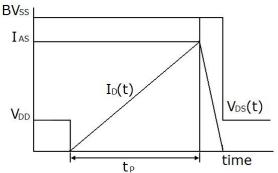
2) Switch Time Test Circuit:





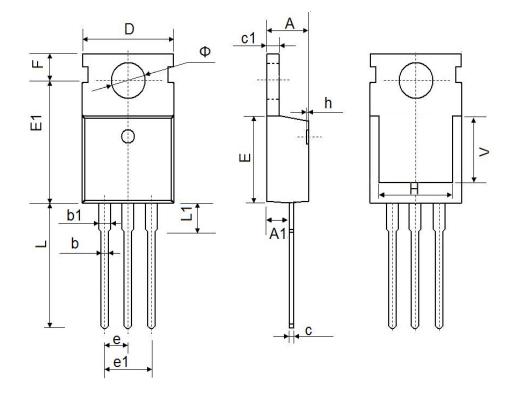
#### 3) Unclamped Inductive Switching Test Circuit & Waveforms







# **TO-220-E Package Information**



Symbol	Dimensions	In Millimeters	Dimensions In Inches		
Cymbol	Min.	Max.	Min.	Max.	
A	4.20	4.60	0.165	0.181	
A1	2.25	2.55	0.089	0.100	
b	0.70	0.90	0.028	0.035	
b1	1.17	1.37	0.046	0.054	
С	0.33	0.65	0.013	0.026	
c1	1.20	1.40	0.047	0.055	
D	9.91	10.25	0.390	0.404	
E	8.95	9.75	0.352	0.384	
E1	12.80	12.90	0.504	0.508	
e	2.54BSC		0.100BSC		
e1	5.08	5.08BSC		BSC	
F	2.65	2.95	0.104	0.116	
Н	7.90	8.10	0.311	0.319	
L	12.90	13.40	0.508	0.528	
L1	2.85	3.25	0.112	0.128	
Φ	3.40	3.80	0.134	0.150	



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